## Notice of References Cited Application/Control No. 09/903,515 Examiner Christopher L Lavin Applicant(s)/Patent Under Reexamination YOU ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,559,551	09-1996	Sakamoto et al.	348/169
	В	US-6,760,465	07-2004	McVeigh et al.	382/103
	С	US-6,731,792	05-2004	Tanaka, Sumiyo	382/164
	D	US-			-
	Е	US-			
	F	US-			
	G	US-			
	Н	US-		·	
	i	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w	,					
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.